[ZnO-12]

Resonant Luminescence of Bound Exciton (A₀,X) and Electron Transport Observed in Zno Grown by Plasma-Assisted Molecular Beam Epitaxy

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We want to discuss very interesting optical and electrical properties of ZnO based on the observation of radiative recombination and in terms of n and. High quality ZnO thin films were grown on LT-ZnO/c-Al₂O₃(1000) single crystal substrate by oxygen plasma assisted molecular beam epitaxy. The ZnO film deposited at 720 oC showed the full-width at half maximum of -rocking curve for ZnO(0002) diffraction line of 80 arcsec and concentration of n=2.5x10¹⁷/cm³ with the high mobility of =105 cm²/Vs. From the PL measurement at 10K-300K, one (Do, X) and two (A₀,X) lines were well resolved at 10 K and were identified as I₃, I₁₀, and I₁₁ respectively by calculating the activation energy obtained from curve fitting of changing intensity. In particular, great increase of the intensity I₁₀ in PL at 50 K was observed and be reasoned by resonance due to the excitation of exciton bound neutral acceptor energy level. From the temperature dependent Hall measurement (T-Hall), it was found that mobility increased from 30 K to 130 K (maximum) and then decreasing and (T) vs. T was fitted by the solving the Boltzmann transport equation using Rode's method. From the results, at lower temperature region mobility strongly depended on both dislocation density and compensation ratio N_A/N_D(ratio of acceptor to donor concentration) and at high temperature the polar optical phonon scattering was regarded as main scattering factor. By the analyzing n vs. T, one donor level of 36 meV for 60K-110K and the other for 110K-300K was obtained. The electron transport and the origin of two shallow donors in undoped high quality ZnO thin film will be discussed.